

### **MOSFET**

### CoolSiC™ MOSFET 650 V G2

Built on Infineon's robust 2<sup>nd</sup> generation Silicon Carbide trench technology, the 650 V CoolSiC<sup>™</sup> MOSFET delivers unparalleled performance, superior reliability, and great ease of use. It enables cost effective, highly efficient, and simplified designs to fulfill the ever-growing system and market needs.

### **Features**

- · Ultra-low switching losses
- Benchmark gate threshold voltage, V<sub>GS(th)</sub> = 4.5 V
- Robust against parasitic turn-on even with 0 V turn-off gate voltage
- Flexible driving voltage and compatible with bipolar driving scheme
- Robust body diode operation under hard commutation events
- .XT interconnection technology for best-in-class thermal performance

### **Benefits**

- · Enables high efficiency and high power density designs
- Facilitates great ease of use and integration
- Provides the best price performance ratio compared to Industry's most ambitious roadmaps
- Reduces the size, weight and bill of materials of the systems
- Enhances system robustness and reliability

### Potential applications

- SMPS
- · Solar PV inverters
- · Energy storage and battery formation
- UPS
- · EV charging infrastructure
- · Motor drives

### **Product validation**

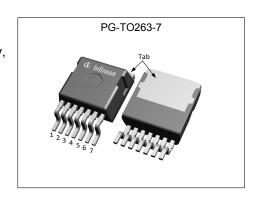
Fully qualified according to JEDEC for Industrial Applications

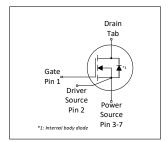
Please note: The source and driver source pins are not exchangeable. Their exchange might lead to malfunction.



Table 1 110y 1 01101111ai100 1 ai ainicioi0								
Parameter	Value	Unit						
$V_{\rm DSS}$ over full $T_{\rm j,range}$	650	V						
R <sub>DS(on),typ</sub>	40	mΩ						
R <sub>DS(on),max</sub>	49	mΩ						
$Q_{G,typ}$	28	nC						
I <sub>D,pulse</sub>	143	A						
Q <sub>oss</sub> @ 400 V	53	nC						
E <sub>oss</sub> @ 400 V	7.2	μJ						

Type / Ordering Code	Package	Marking	Related Links
IMBG65R040M2H	PG-TO263-7	65R040M2	see Appendix A













## **Table of Contents**

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1 Maximum ratings at  $T_j = 25$  °C, unless otherwise specified.

Note: for optimum lifetime and reliability, Infineon recommends operating conditions that do not exceed 80% of the maximum ratings stated in this datasheet.

Table 2 Maximum ratings

Danamastan	Ob. a.l.		Value	s			
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Continuous DC drain current <sup>1)</sup>	I <sub>DDC</sub>	-	-	49 34	А	T <sub>C</sub> = 25 °C T <sub>C</sub> = 100 °C	
Peak drain current <sup>2)</sup>	<b>I</b> <sub>DM</sub>	-	-	143	Α	T <sub>C</sub> = 25 °C, V <sub>GS</sub> = 18 V	
Avalanche energy, single pulse	<b>E</b> AS	-	-	132	mJ	$I_D = 4.9 \text{ A}, V_{DD} = 50 \text{ V}; \text{ see table } 11$	
Avalanche energy, repetitive	<b>E</b> AR	-	-	0.66	mJ	$I_{\rm D}$ = 4.9 A, $V_{\rm DD}$ = 50 V; see table 11	
Avalanche current, single pulse	I <sub>AS</sub>	-	-	4.9	Α	-	
MOSFET dv/dt ruggedness	dv/dt	-	-	200	V/ns	V <sub>DS</sub> = 0400 V	
Gate source voltage (static) <sup>3)</sup>	V <sub>GS</sub>	-7	-	23	V	-	
Gate source voltage (transient)	V <sub>GS</sub>	-10	-	25	V	$t_p \le 500 \text{ ns}, \text{ duty cycle} \le 1 \%$	
Power dissipation	P <sub>tot</sub>	-	-	197	W	T <sub>C</sub> = 25 °C	
Storage temperature	$T_{ m stg}$	-55	-	150	°C	-	
Operating junction temperature	T <sub>j</sub>	-55	-	175	°C	-	
Mounting torque	-	-	-	-	Ncm	-	
Continuous reverse drain current <sup>1)</sup>	I <sub>SDC</sub>	-	-	49 33.6	А	V <sub>GS</sub> = 18 V, T <sub>C</sub> = 25 °C V <sub>GS</sub> = 0 V, T <sub>C</sub> = 25 °C	
Peak reverse drain current <sup>2)</sup>	I <sub>SM</sub>	-	-	143 43 A $T_{\rm C} = 25 ^{\circ}{\rm C}, t_{\rm p} \le 250 \text{ns}$ $T_{\rm C} = 25 ^{\circ}{\rm C}$			
Insulation withstand voltage	V <sub>ISO</sub>	-	-	n.a.	V	$V_{\rm rms}$ , $T_{\rm C}$ = 25 °C, $t$ = 1 min	

<sup>&</sup>lt;sup>1)</sup> Limited by  $T_{\rm J,max}$ <sup>2)</sup> Pulse width  $t_{\rm pulse}$  limited by  $T_{\rm j,max}$ .
<sup>3)</sup> The maximum gate-source voltage in the application design should be in accordance to IPC-9592B.



## 2 Thermal characteristics

**Table 3** Thermal characteristics

Damamatan	Cymphal	Values			11:4	Nata / Tant Canalitian
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Thermal resistance, junction - case	R <sub>th(j-c)</sub>	-	-	0.76	°C/W	Not subject to production test. Parameter verified by design/characterization according to JESD51-14.
Soldering temperature, reflow soldering allowed	$T_{sold}$	-	-	260	°C	reflow MSL1

## 3 Operating range

Table 4 Operating range

Davamatav	Cumbal	Values			l lmi4	Note / Took Condition
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Recommended turn-on voltage	V <sub>GS(on)</sub>	-	18	-	V	-
Recommended turn-off voltage	V <sub>GS(off)</sub>	-	0	-	V	-

## CoolSiC™ MOSFET 650 V G2

IMBG65R040M2H



# 4 Electrical characteristics at $T_j = 25$ °C, unless otherwise specified

#### Table 5 **Static characteristics**

Parameter		Values				
	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Drain-source voltage	V <sub>DSS</sub>	650	-	-	V	$V_{\rm GS}$ = 0 V, $I_{\rm D}$ = 0.46 mA
Gate threshold voltage <sup>1)</sup>	V <sub>GS(th)</sub>	3.5	4.5	5.6	V	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 4.6 \text{ mA}$
Zero gate voltage drain current	I <sub>DSS</sub>	-	1 3	75 -	μΑ	$V_{\rm DS} = 650 \text{ V}, \ V_{\rm GS} = 0 \text{ V}, \ T_{\rm j} = 25 \text{ °C} $ $V_{\rm DS} = 650 \text{ V}, \ V_{\rm GS} = 0 \text{ V}, \ T_{\rm j} = 175 \text{ °C} $
Gate-source leakage current	I <sub>GSS</sub>	-	-	100	nA	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V
Drain-source on-state resistance	R <sub>DS(on)</sub>	- - - -	52 40 36 65	- 49 - -	mΩ	$V_{\rm GS}$ = 15 V, $I_{\rm D}$ = 22.9 A, $T_{\rm j}$ = 25 °C $V_{\rm GS}$ = 18 V, $I_{\rm D}$ = 22.9 A, $T_{\rm j}$ = 25 °C $V_{\rm GS}$ = 20 V, $I_{\rm D}$ = 22.9 A, $T_{\rm j}$ = 25 °C $V_{\rm GS}$ = 18 V, $I_{\rm D}$ = 22.9 A, $T_{\rm j}$ =175 °C
Internal gate resistance	$R_{G,int}$	-	3.4	-	Ω	f = 1 MHz

 $<sup>^{1)}</sup>$  Tested after 1 ms pulse at V<sub>GS</sub> = +20 V. "Linear mode" operation is not recommended. For assessment of potential "linear mode" operation, please contact Infineon sales office.



#### Table 6 **Dynamic characteristics**

External parasitic elements (PCB layout) influence switching behavior significantly. Stray inductances and coupling capacitances must be minimized.

For layout recommendations please use provided application notes or contact Infineon sales office.

Damanastan	0		Values				
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Input capacitance	Ciss	-	997	-	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}, f = 250 \text{ kHz}$	
Reverse transfer capacitance	C <sub>rss</sub>	-	5.8	-	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}, f = 250 \text{ kHz}$	
Output capacitance <sup>1)</sup>	Coss	-	74	96	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}, f = 250 \text{ kHz}$	
Output charge <sup>1)</sup>	Qoss	-	53	69	nC	calculation based on Coss	
Effective output capacitance, energy related <sup>2)</sup>	C <sub>o(er)</sub>	-	90	-	pF	$V_{GS} = 0 \text{ V},$ $V_{DS} = 0400 \text{ V}$	
Effective output capacitance, time related <sup>3)</sup>	C <sub>o(tr)</sub>	-	133	-	pF	$I_D$ = constant, $V_{GS}$ = 0 V, $V_{DS}$ = 0400 V	
Turn-on delay time	$t_{\sf d(on)}$	-	8.4	-	ns	$V_{\rm DD} = 400 \text{ V}, V_{\rm GS} = 0/18 \text{ V}, I_{\rm D} = 22.9 \text{ A}, R_{\rm G,ext} = 1.8 \Omega;$ see table 10	
Rise time	t <sub>r</sub>	-	8.3	-	ns	$V_{\rm DD} = 400 \text{ V}, V_{\rm GS} = 0/18 \text{ V}, I_{\rm D} = 22.9 \text{ A}, R_{\rm G,ext} = 1.8 \Omega;$ see table 10	
Turn-off delay time	$t_{ m d(off)}$	-	14.4	-	ns	$V_{\rm DD} = 400 \text{ V}, V_{\rm GS} = 0/18 \text{ V}, I_{\rm D} = 22.9 \text{ A}, R_{\rm G,ext} = 1.8 \Omega;$ see table 10	
Fall time	t <sub>f</sub>	-	4.6	-	ns	$V_{\rm DD} = 400 \text{ V}, V_{\rm GS} = 0/18 \text{ V}, I_{\rm D} = 22.9 \text{ A}, R_{\rm G,ext} = 1.8 \Omega;$ see table 10	
Turn-ON switching losses <sup>4)</sup>	E <sub>on</sub>	-	30	-	μJ	$V_{\rm DD} = 400 \text{ V}, V_{\rm GS} = 0/18 \text{ V}, I_{\rm D} = 22.9 \text{ A}, R_{\rm G,ext} = 1.8 \Omega$	
Turn-OFF switching losses <sup>4)</sup>	E <sub>off</sub>	-	16	-	μJ	$V_{\rm DD} = 400 \text{ V}, V_{\rm GS} = 0/18 \text{ V}, I_{\rm D} = 22.9 \text{ A}, R_{\rm G,ext} = 1.8 \Omega$	
Total switching losses <sup>4)</sup>	E <sub>tot</sub>	-	46	-	μJ	$V_{\rm DD} = 400 \text{ V}, V_{\rm GS} = 0/18 \text{ V}, I_{\rm D} = 22.9 \text{ A}, R_{\rm G,ext} = 1.8 \Omega$	

Table 7 Gate charge characteristics

Davamatav	Sumbol	Values			11	Note / Took Condition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Plateau gate to source charge	Q <sub>GS(pl)</sub>	-	7.3	-	nC	$V_{\text{DD}} = 400 \text{ V}, I_{\text{D}} = 22.9 \text{ A}, V_{\text{GS}} = 0 \text{ to } 18 \text{ V}$	
Gate to drain charge	$Q_{GD}$	-	5.3	-	nC	$V_{\rm DD}$ = 400 V, $I_{\rm D}$ = 22.9 A, $V_{\rm GS}$ = 0 to 18 V	
Total gate charge	$Q_G$	-	28	-	nC	$V_{\rm DD}$ = 400 V, $I_{\rm D}$ = 22.9 A, $V_{\rm GS}$ = 0 to 18 V	

 $<sup>^{1)}</sup>$  Maximum specification is defined by calculated six sigma upper confidence bound  $^{2)}$   $C_{o(er)}$  is a fixed capacitance that gives the same stored energy as  $C_{\rm oss}$  while  $V_{\rm DS}$  is rising from 0 to 400 V.  $^{3)}$   $C_{\rm o(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{\rm oss}$  while  $V_{\rm DS}$  is rising from 0 to 400 V.  $^{4)}$  MOSFET used in half-bridge configuration without external diode

## CoolSiC™ MOSFET 650 V G2



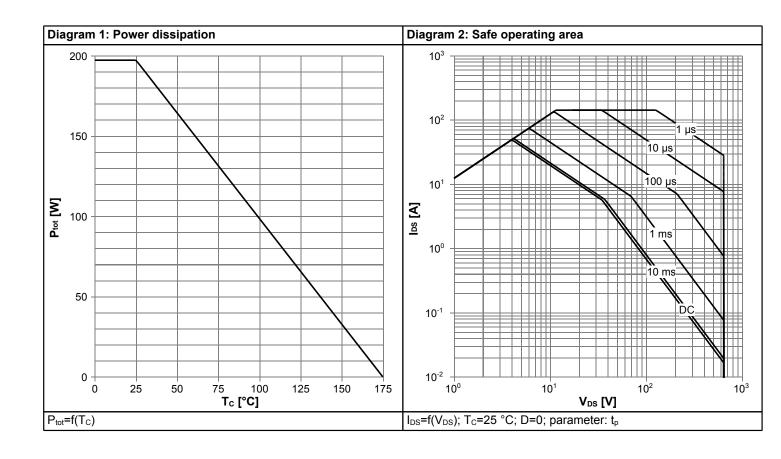


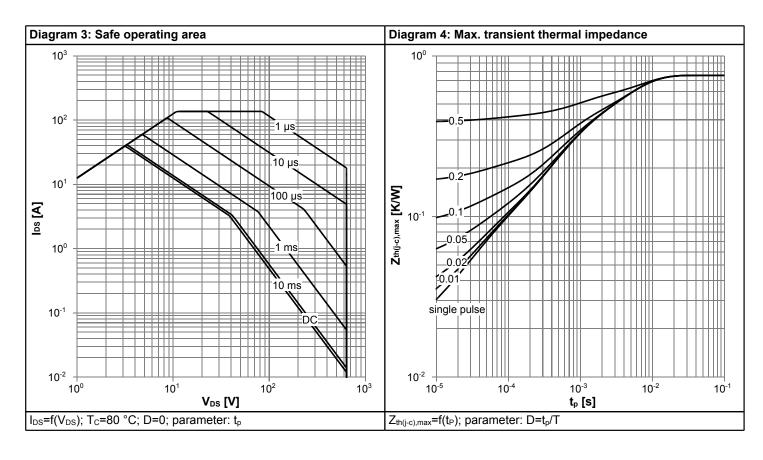
Table 8 Reverse diode characteristics

Bananatan	Oh a l	Values				
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Drain-source reverse voltage	V <sub>SD</sub>	-	4.3	-	V	$V_{GS} = 0 \text{ V}, I_{S} = 22.9 \text{ A}, T_{j} = 25 ^{\circ}\text{C}$
MOSFET forward recovery time	<b>t</b> fr	-	12.2 7.6	-	ns	$V_{\rm DD} = 400 \text{ V}, I_{\rm S} = 22.9 \text{ A},$ $di_{\rm S}/dt = 1000 \text{ A/}\mu\text{s}; \text{ see table 9}$ $V_{\rm DD} = 400 \text{ V}, I_{\rm S} = 22.9 \text{ A},$ $di_{\rm S}/dt = 4000 \text{ A/}\mu\text{s}; \text{ see table 9}$
MOSFET forward recovery charge <sup>1)</sup> Q <sub>fr</sub>		-	56 82	-	nC	$V_{\rm DD} = 400 \text{ V}, I_{\rm S} = 22.9 \text{ A},$ $di_{\rm S}/dt = 1000 \text{ A/}\mu\text{s}; \text{ see table 9}$ $V_{\rm DD} = 400 \text{ V}, I_{\rm S} = 22.9 \text{ A},$ $di_{\rm S}/dt = 4000 \text{ A/}\mu\text{s}; \text{ see table 9}$
MOSFET peak forward recovery current	<b>I</b> frm	-	9.1 21.6	-	A	$V_{\rm DD} = 400 \text{ V}, I_{\rm S} = 22.9 \text{ A},$ $di_{\rm S}/dt = 1000 \text{ A/µs}; \text{ see table 9}$ $V_{\rm DD} = 400 \text{ V}, I_{\rm S} = 22.9 \text{ A},$ $di_{\rm S}/dt = 4000 \text{ A/µs}; \text{ see table 9}$

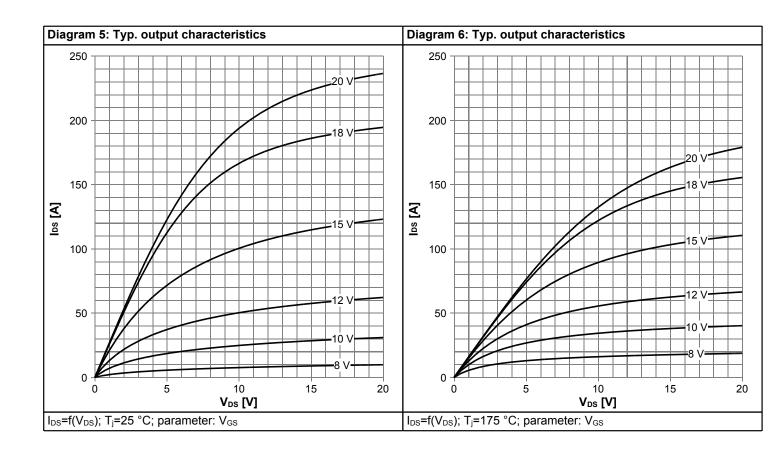


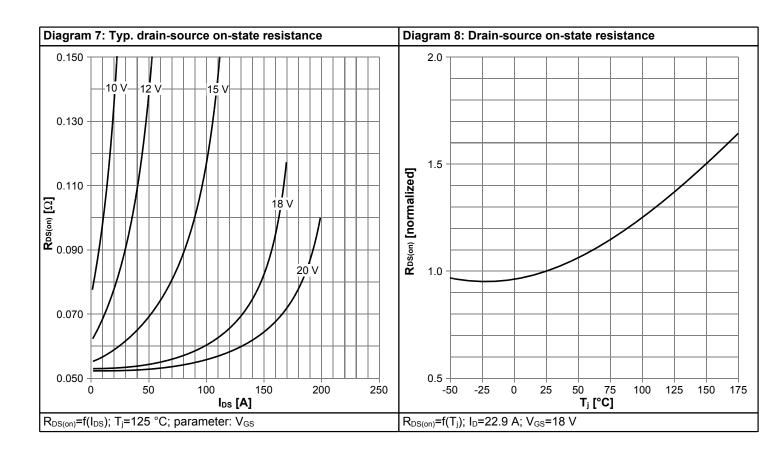
## 5 Electrical characteristics diagrams



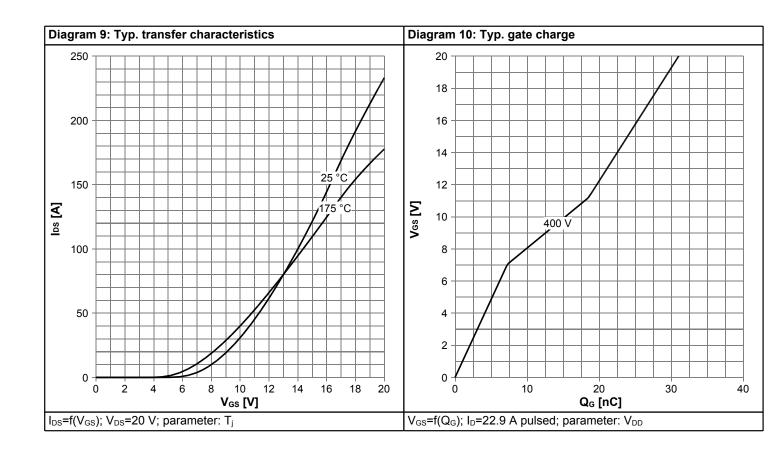


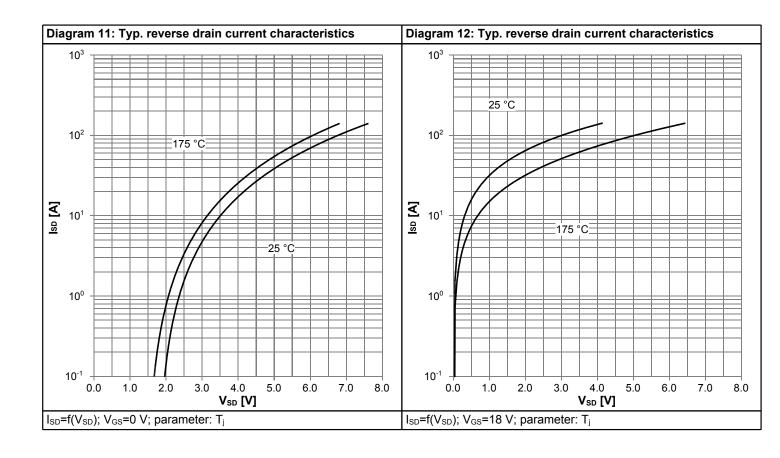




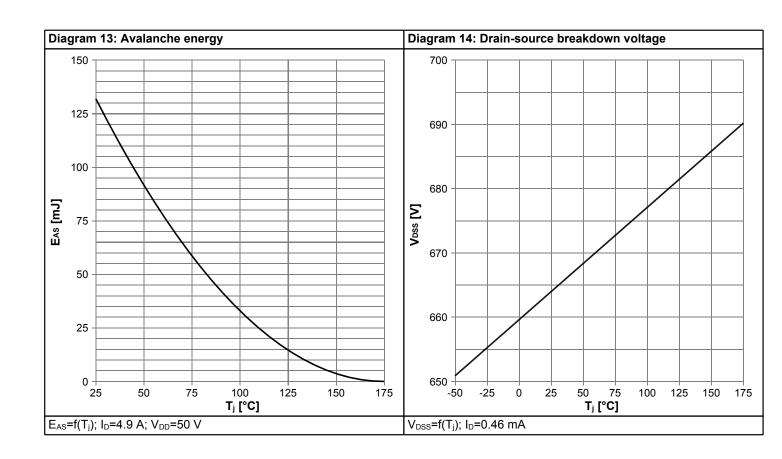


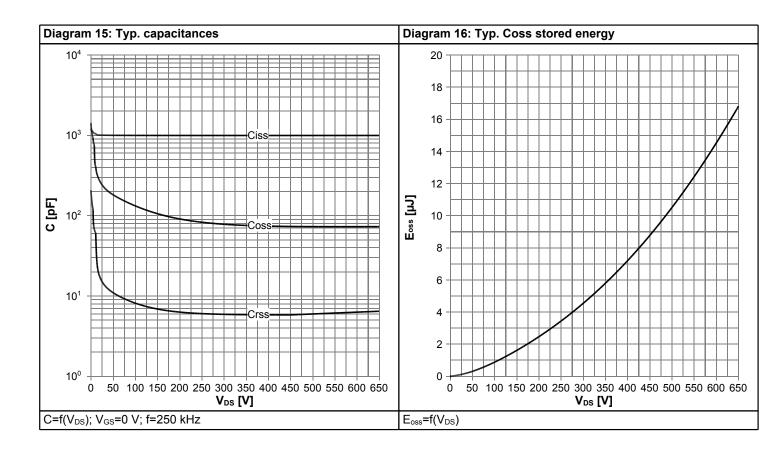




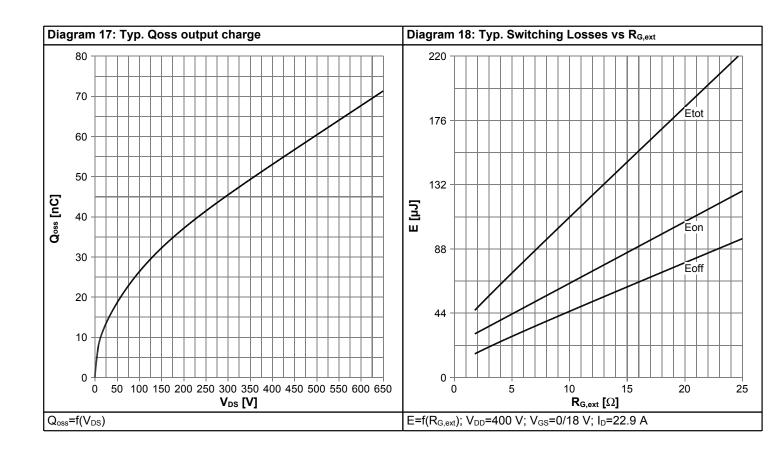


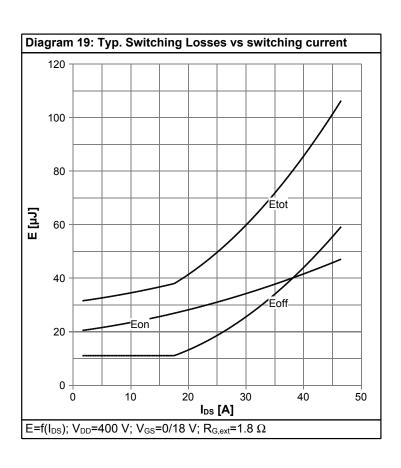














### 6 Test Circuits

Table 9 Body diode characteristics

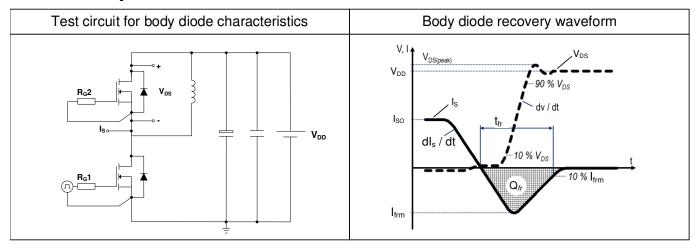


Table 10 Switching times

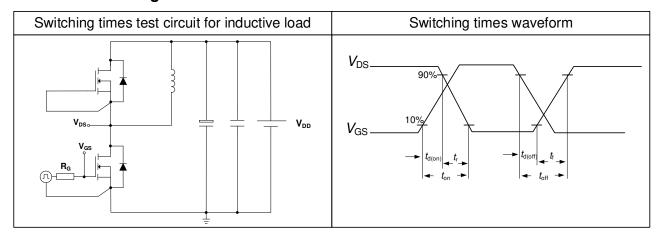
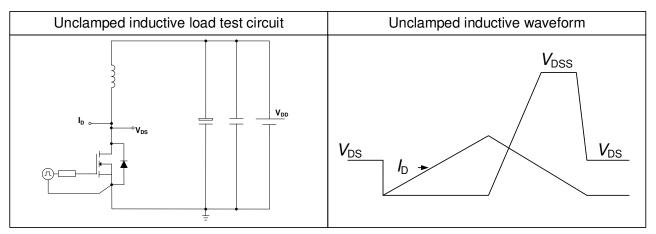


Table 11 Unclamped inductive load





## 7 Package Outlines

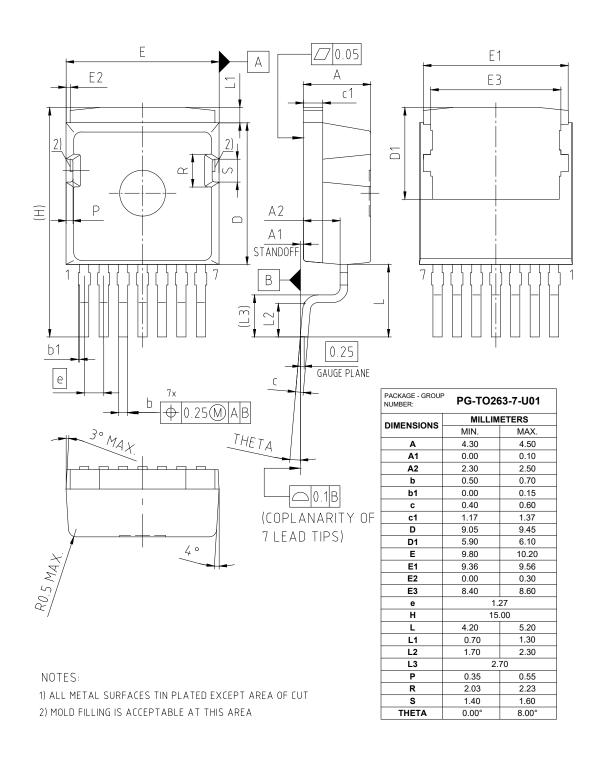


Figure 1 Outline PG-TO263-7, dimensions in mm



## 8 Appendix A

### Table 12 Related Links

- IFX CoolSiC CoolSiC™ MOSFET 650 V G2 Webpage: www.infineon.com
- IFX CoolSiC CoolSiC™ MOSFET 650 V G2 application note: www.infineon.com
- IFX CoolSiC CoolSiC™ MOSFET 650 V G2 simulation model: www.infineon.com
- IFX Design tools: www.infineon.com

## CoolSiC™ MOSFET 650 V G2





### **Revision History**

IMBG65R040M2H

Revision: 2024-03-05, Rev. 2.2

**Previous Revision** 

Revision	Date	Subjects (major changes since last revision)
2.0	2023-09-26	Release of final version
2.1	2024-02-29	updated simulation model; included Eon and Eoff data and diagrams
2.2	2024-03-05	minor layout changes

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